

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: April 15, 2005

ATTY DOCKET NO.
OCEANITSERIAL NO.
10/693,953APPLICANT
O'CONNELL, Daniel G.FILING DATE
October 28, 2003

GROUP

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
K.G.	AA	6,208,886	3/27/2001	Alfano et al.			
K.G.	AB	6,818,907	11/16/2004	Stark			
K.G.	AC	2003/0215844	11/20/2003	Chapsky et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL						
	AM						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

K.G.	AN	Milster et al.; <u>Super-Resolution by Combination of a Solid Immersion Lens and Aperture</u> ; The Japanese Society of Applied Physics, Part 1, No.3B: March 2001
K.G.	AO	Hecht et al.; <u>scanning near-field optical microscopy with aperture probes: Fundamentals and applications</u> ; Special Topic: Near-field Microscopy and Spectroscopy; Journal of Chemical Physics; Vol. 112, No.18; May 8, 2000
K.G.	AP	Betzig & Chichester; <u>Single Molecules Observed by Near-field Scanning Optical Microscopy</u> ; Science, New Series; Vol. 262, No.5138; November 26, 1993; Pages 1422-1425
K.G.	AQ	Mansfield & Kino; <u>Solid Immersion Microscope</u> ; Appl. Physics Letter; Vol.57, No. 24; December 10, 1990

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: April 21, 2005

ATTY DOCKET NO.
OCEANITSERIAL NO.
10/693,953APPLICANT
O'CONNELL, Daniel G.FILING DATE
October 28, 2003

GROUP

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AC						
	AD						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

K.G.	AE	D. V. Palanker et al.; <u>On contrast parameters and topographic artifacts in near-field infrared microscopy</u> ; Journal of Applied Physics, Vol. 88, No. 11; December 1, 2000
K.G.	AF	Tom D. Milster et al.; <u>The Nature of the Coupling field in Optical Data Storage using Solid Immersion Lenses</u> ; The Japanese Society of Applied Physics, Part 1, No. 3B: March 1999
K.G.	AG	Jonathan D. Bui et al.; <u>Probing intracellular dynamics in living cells with near-field optics</u> ; Journal of Neuroscience Methods 89 (1999) 9-15; February 27, 1999
	AH	
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EXAMINER		DATE CONSIDERED

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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
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Date Submitted to PTO: April 27, 2005

ATTY DOCKET NO.
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O'CONNELL, Daniel G.FILING DATE
October 28, 2003

GROUP

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
K.G.	AA	5,004,307	4/2/1991	Kino et al.			
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	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
	AL							
	AM							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

K.G.	AN	Tang et al.; <u>Consideration and control of writing conditions with a near-field APSIL probe</u> ; Proceedings of International Symposium on Optical Memory and Optical Data Storage/2002; ISBN 0-7803-7379-0; Published:2002; Pages 243-245
	AO	
	AP	
	AQ	

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DATE CONSIDERED

3/06

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